

Notice of References Cited	Application/Control No. 10/696,431	Applicant(s)/Patent Under Reexamination HAN ET AL.
	Examiner Paul D. Kim	Art Unit 3729

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0048578 A1	03-2003	Kikuchi et al.	360/123
*	B	US-6,101,071	08-2000	Kouchiyama, Akira	360/324
	C	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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